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Amendments to the Claims:

This listing of claims will replace all prior versions, and listings, of claims in the application:

Listing of Claims:

Claim 1 (currently amended): An integrated module,  
comprising:

an external access terminal;

a memory including memory cells for storing code and data;

a microcontroller connected to said external access terminal and to said memory, said microcontroller controlling an access to said memory and a data transfer through said external access terminal during normal operation, said microcontroller controlling a performance of a test sequence for functional testing said memory in a test operation of the module; and

a defect data memory for storing addresses of the memory cells of said memory which have been detected as defective, said addresses being generated during the functional testing, said addresses being stored in said defect data memory under control of said microcontroller, said addresses further being read out under control of said microcontroller, to outside of the integrated module.

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Claim 2 (original): The integrated module according to claim 1, further comprising a command memory for storing an externally supplied command sequence and on a basis of the command sequence said microcontroller controls a carrying out of the test sequence.

Claim 3 (original): The integrated module according to claim 1, wherein said defect data memory is part of said microcontroller.

Claim 4 (original): The integrated module according to claim 2, wherein said command memory is part of said microcontroller.

Claim 5 (currently amended): A method for functionally checking a memory of an integrated module, which comprises the steps of:

reading-in a command sequence externally before beginning a test operation, and on a basis of the command sequence a microcontroller controls a carrying out of a test sequence;

executing the command sequence for carrying out the test sequence by the microcontroller; and

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storing addresses of memory cells of the memory which have been detected as defective during the functional testing in a defect data memory, said addresses being stored in said defect data memory under control of said microcontroller; and

reading-out the addresses of the memory cells of the memory which have been detected as defective during functional testing stored in the defect data memory, under the control of the microcontroller, to outside the integrated module for further evaluation.

Claim 6 (currently amended): The method according to claim 5, which further comprises:

making a jump to a start address in an internal command memory after the command sequence is read-in at the beginning of the test operation;

executing the command sequence under the control of the microcontroller proceeding from the start address; and

storing the addresses of the memory cells of the memory which have been detected as defective during functional testing

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generated in the defect data memory under the control of the  
microcontroller, ~~and~~

~~reading out the addresses of the memory cells of the memory  
which have been detected as defective during functional  
testing stored in the defect data memory, under the control of  
the microcontroller, to outside the integrated module for  
further evaluation.~~

Claim 7 (previously presented): The integrated module  
according to claim 1, wherein said defect data memory and said  
command memory are part of a dual-port RAM.

Claim 8 (previously presented): The integrated module  
according to claim 1, wherein the microcontroller is embodied  
as a hard disk controller.